

LVT16 family characteristics

Family specifications

FAMILY DESCRIPTION

The LVT16 family comprises very fast low-power logic ICs fabricated in an advanced sub-micron BiCMOS process.

LVT16 ICs at a supply voltage of 3.3V operate at the same speed as ABT BiCMOS logic at $V_{CC} = 5V$ and they consume considerably less power.

The LVT16 family functions down to $V_{CC} = 2.7V$ for application in unregulated systems and provides a number of extra features not found in other logic families.

The reduction from the standard 5.0V to 3.3V reduces the output swing, leading to a much lower power dissipation. Pin and function compatibility with ABT16 ensure an easy transfer of existing systems into new 3.3V systems.

HANDLING BICMOS DEVICES

Inputs and outputs are protected against electrostatic effects in a wide variety of device-handling situations.

ABSOLUTE MAXIMUM RATINGS¹, NO TAG

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V_{CC}	DC supply voltage		-0.5 to +4.6	V
I_{IK}	DC input diode current	$V_I < 0$	-50	mA
V_I	DC input voltage ³		-0.5 to +7.0	V
I_{OK}	DC output diode current	$V_O < 0$	-50	mA
V_{OUT}	DC output voltage ³	Output in Off or High state	-0.5 to +7.0	V
I_{OUT}	DC output current	Output in Low state	128	mA
		Output in High state	-64	
T_{stg}	Storage temperature range		-65 to +150	°C

NOTES:

- Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
- The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS		UNIT
		MIN	MAX	
V_{CC}	DC supply voltage	2.7	3.6	V
V_I	Input voltage	0	5.5	V
V_{IH}	High-level input voltage	2.0		V
V_{IL}	Input voltage		0.8	V
I_{OH}	High-level output current		-32	mA
I_{OL}	Low-level output current		32	mA
	Low-level output current; current duty cycle $\leq 50\%$; $f \geq 1kHz$		64	
$\Delta t/\Delta v$	Input transition rise or fall rate; Outputs enabled		10	ns/V
T_{amb}	Operating free-air temperature range	-40	+85	°C

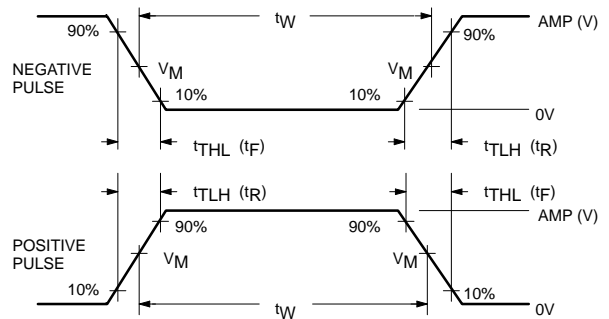
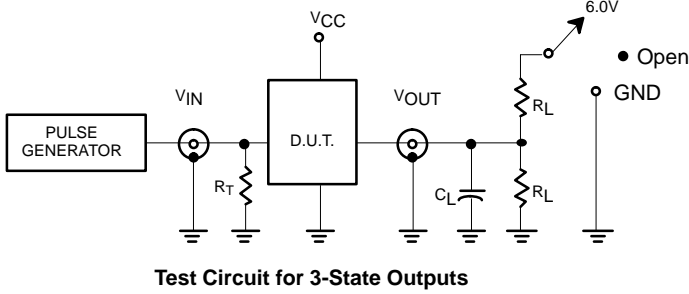
DC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS			UNIT
			Temp = -40°C to +85°C			
			MIN	TYP ¹	MAX	
V _{IK}	Input clamp voltage	V _{CC} = 2.7V; I _{IK} = -18mA		-0.85	-1.2	V
V _{OH}	High-level output voltage	V _{CC} = 2.7 to 3.6V; I _{OH} = -100μA	V _{CC} -0.2	V _{CC}		V
		V _{CC} = 2.7V; I _{OH} = -8mA	2.4	2.55		
		V _{CC} = 3.0V; I _{OH} = -32mA	2.0	2.30		
V _{OL}	Low-level output voltage	V _{CC} = 2.7V; I _{OL} = 100μA		0.07	0.2	V
		V _{CC} = 2.7V; I _{OL} = 24mA		0.3	0.5	
		V _{CC} = 3.0V; I _{OL} = 16mA		0.25	0.4	
		V _{CC} = 3.0V; I _{OL} = 32mA		0.3	0.5	
		V _{CC} = 3.0V; I _{OL} = 64mA		0.36	0.55	
V _{RST}	Power-up output low voltage ⁵	V _{CC} = 3.6V; I _O = 1mA; V _I = GND or V _{CC}		0.1	0.55	V
I _I	Input leakage current	V _{CC} = 3.6V; V _I = V _{CC} or GND	Control pins	0.1	±1	μA
		V _{CC} = 0 or 3.6V; V _I = 5.5V		0.1	10	
		V _{CC} = 3.6V; V _I = 5.5V	I/O Data pins ⁴	1.0	20	
		V _{CC} = 3.6V; V _I = V _{CC}		0.1	10	
		V _{CC} = 3.6V; V _I = 0		0.1	-5	
I _{OFF}	Output off current	V _{CC} = 0V; V _I or V _O = 0 to 4.5V		1.0	±100	μA
I _{HOLD}	Bus Hold current	V _{CC} = 3V; V _I = 0.8V	75	130		μA
	A or B outputs	V _{CC} = 3V; V _I = 2.0V	-75	-130		
I _{EX}	Current into an output in the High state when V _O > V _{CC}	V _O = 5.5V; V _{CC} = 3.0V		50	125	μA
I _{PU/PD}	Power up/down 3-State output current ³	V _{CC} ≤ 1.2V; V _O = 0.5V to V _{CC} ; V _I = GND or V _{CC} ; OE/OĒ = Don't care		40	±100	μA
I _{CCH}	Quiescent supply current	V _{CC} = 3.6V; Outputs High, V _I = GND or V _{CC} , I _O = 0		0.07	0.12	mA
I _{CCL}		V _{CC} = 3.6V; Outputs Low, V _I = GND or V _{CC} , I _O = 0		4	6	
I _{CCZ}		V _{CC} = 3.6V; Outputs Disabled; V _I = GND or V _{CC} , I _O = 0 ⁶		0.07	0.12	
ΔI _{CC}	Additional supply current per input pin ²	V _{CC} = 3V to 3.6V; One input at V _{CC} -0.6V, Other inputs at V _{CC} or GND		0.1	0.2	mA

NOTES:

- All typical values are at V_{CC} = 3.3V and T_{amb} = 25°C.
- This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND
- This parameter is valid for any V_{CC} between 0V and 1.2V with a transition time of up to 10msec. From V_{CC} = 1.2V to V_{CC} = 3.3V ± 0.3V a transition time of 100μsec is permitted. This parameter is valid for T_{amb} = 25°C only.
- Unused pins at V_{CC} or GND.
- For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.
- I_{CCZ} is measured with outputs pulled to V_{CC} or GND.

TEST CIRCUIT AND WAVEFORMS



SWITCH POSITION

TEST	SWITCH
t_{PLZ}/t_{PZL}	6V
t_{PLH}/t_{PHL}	Open
t_{PHZ}/t_{PZH}	GND

DEFINITIONS

- R_L = Load resistor; see AC CHARACTERISTICS for value.
- C_L = Load capacitance includes jig and probe capacitance: See AC CHARACTERISTICS for value.
- R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_W	t_R	t_F
74LVT16	2.7V	$\leq 10MHz$	500ns	$\leq 2.5ns$	$\leq 2.5ns$

SW00040